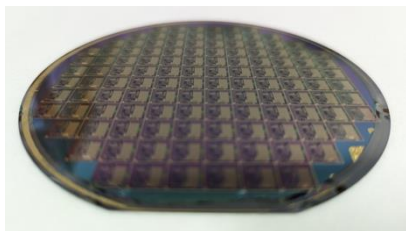


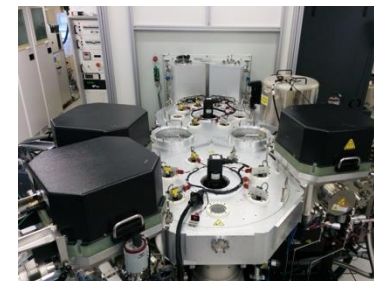
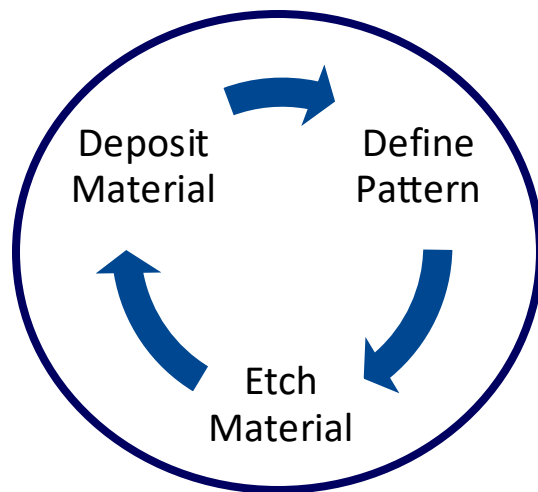


Electrum Laboratory

- 1300 m² cleanroom
- ISO 9001 certified / controlled processes and calibrated characterization tools
- Users: ~50 % academia and ~50% start-up/SME/RISE
- KTH + 20 other entites in 2024 (>100 individuals)



- **Silicon Technology**
- Silicon – Integrated Circuits
- Silicon - Microsystems
- **Compound Semiconductors**
- SiC – High Voltage – High power, Harsh environment
- InP, GaAs, InGaAs... - opto-electronic, Infrared Imaging



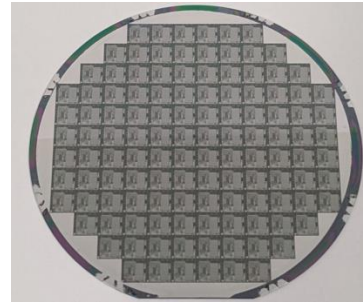
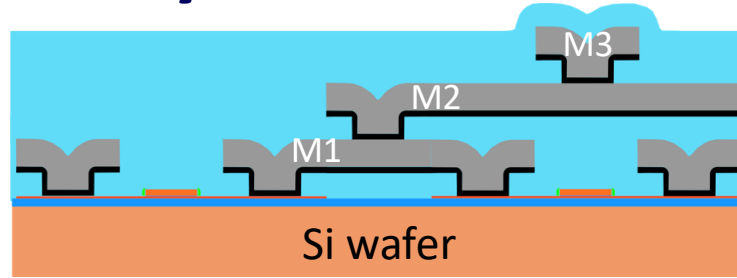
myfab

www.myfab.se

Cleanrooms in KTH, Uppsala, Lund and Chalmers

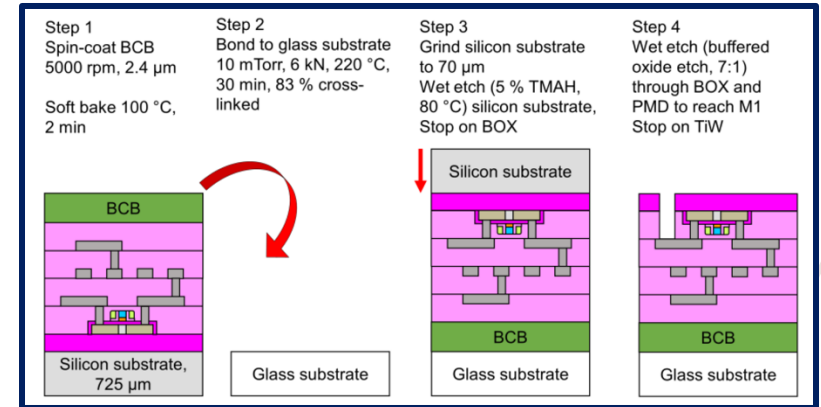
CMOS electronics in Electrum Laboratory

- 13 Patterning Masks
- > 40 individual process steps
- Turn around ~ 3 months
- Full Digital Design flow in Cadence
 - 10 track Cell library, P&R, timing
 - D Flip Flop is Height/Width 40/108 μm

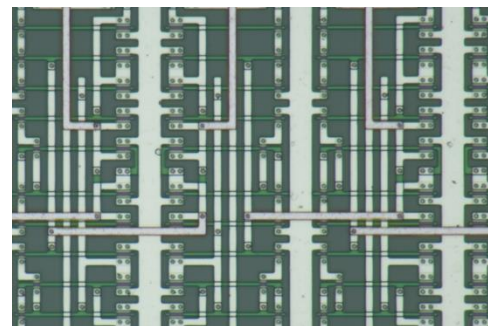
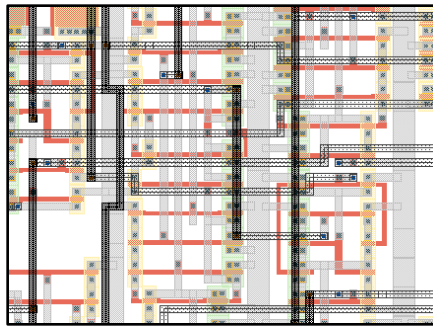
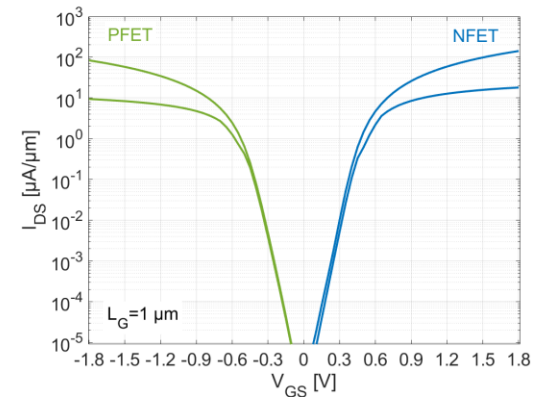
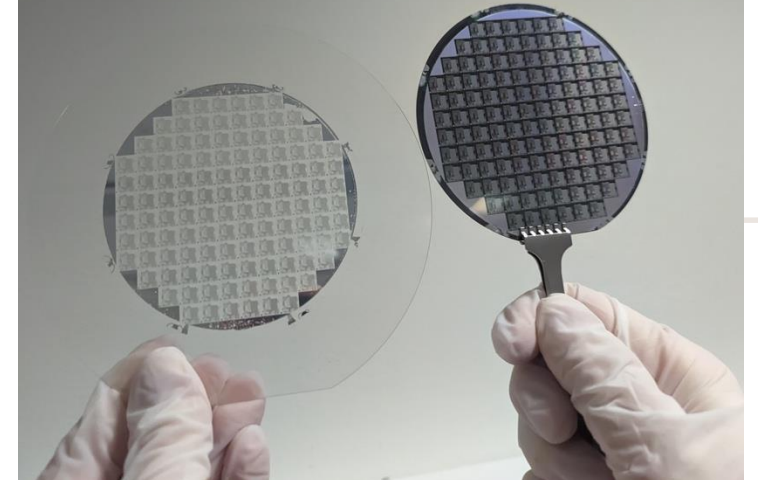


Research field: Transparent Si electronics

Prof. Per-Erik Hellström (EES)
 Mattias Ekström (EES)
 Prof. Frank Niklaus (MST)
 Arne Quelmatz (MST)



First demonstration of semi-transparent Si CMOS



High Voltage SiC Bipolar Transistors (>3.3 kV)

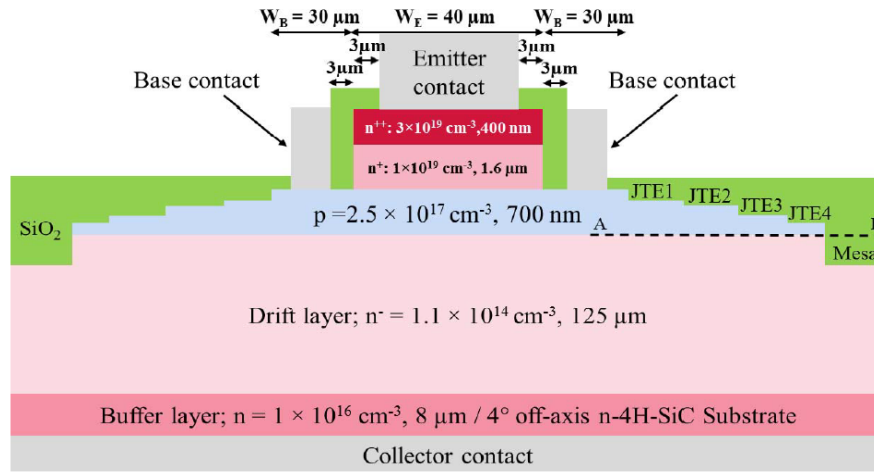


Fig. 1. Schematic cross-sectional view of the fabricated 4H-SiC BJT.

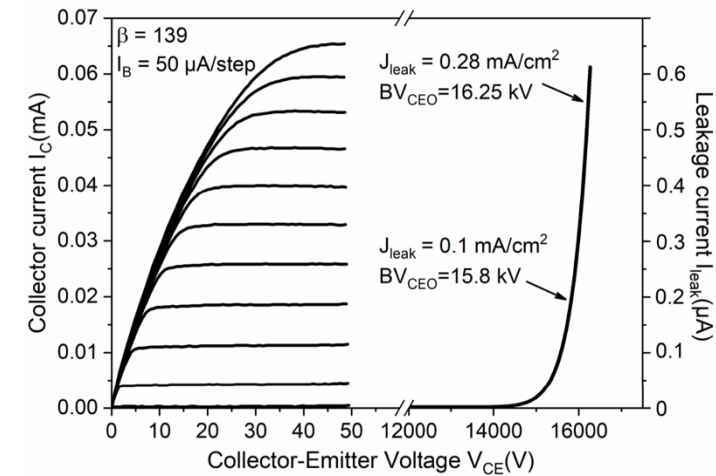


Fig. 2. Room temperature I - V characteristics of the fabricated 0.08 mm^2 (active area of 0.18 mm^2) 4H-SiC BJTs with emitter width of $40 \text{ }\mu\text{m}$.

A. Salemi, H. Elahipanah, K. Jacobs, C. -M. Zetterling and M. Östling, "**15 kV-Class Implantation-Free 4H-SiC BJTs With Record High Current Gain**," in IEEE Electron Device Letters, vol. 39, no. 1, pp. 63-66, Jan. 2018, doi: 10.1109/LED.2017.2774139.

- EU Chips Act: Pilot line Advanced semiconductor devices based on Wide Bandgap materials (2025-2030) <https://www.chips-ju.europa.eu/pilot-lines-detail/>
- KTH's part is to:
 - Deliver devices based on the available SiC Bipolar Junction Transistor (BJT) technology that has been demonstrated to sustain up to 15 kV of collector-emitter voltage.
 - Initially offer BJT devices for 3-5 kV (TRL level 5) on 150 mm SiC wafers.
 - Research and develop Insulated Gate Bipolar Junction Transistors (IGBT) in 150 mm SiC wafers.
 - In-house available innovative, basal plane dislocation-free, 150 mm SiC substrates from KISAB (<https://kisabsemi.com/>) and SiC epitaxy from Coherent (www.coherent.com).